## JC12 Rec'd PCT/PTC $25_{\text{page}} \underline{APR} \underline{2005}$

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					APPLICANT: Thomas Chudoba et al.							
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JD	AA	5,051,594	09/1991	Fumih	iko et al							
JD	АВ	4,157,818	06/1979	Key								
JD	AC	3,201,980	08/1965	Webb								
ற	AD	5,343,748	09/1994	Kease	ey, et al.							
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JD	AL.	WO 02 16907	02/2002	PCT					763	NO		
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JD	"Microscratch and Load Relaxation Tests for Ultra-Thin Films" - Wu T. W. Journal of Materials Research, New York, NY, U.S., Vol. 6, no. 2, pages 407-426 February 1991											
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